

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of: **Kenji WATANABE et al.**

Serial Number: **Not yet assigned**
(§371 of international application No. PCT/JP2004/000711)

Filed: **July 25, 2005**

For: **MAPPING-PROJECTION-TYPE ELECTRON BEAM APPARATUS
FOR INSPECTING SAMPLE BY USING ELECTRONS EMITTED
FROM THE SAMPLE**

Attorney Docket Number: **052886**
Customer Number: **38834**

PRELIMINARY AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

July 25, 2005

Sir:

Prior to calculation of the filing fee and examination of this application, please amend the
above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims that begins on page 2 of this
paper.

Remarks begin on page 5 of this paper.